



# STP10NK50Z

N-channel 500 V, 0.55  $\Omega$ , 9 A Zener-protected SuperMESH™  
Power MOSFETs in TO-220 package

Datasheet — obsolete product

## Features

| Order code | V <sub>DSS</sub> | R <sub>DS(on)</sub> max | I <sub>D</sub> | P <sub>TOT</sub> |
|------------|------------------|-------------------------|----------------|------------------|
| STP10NK50Z | 500 V            | < 0.7 $\Omega$          | 9 A            | 125 W            |

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

## Applications

- Switching application

## Description

These devices are N-channel Zener-protected Power MOSFETs developed using STMicroelectronics' SuperMESH™ technology, achieved through optimization of ST's well established strip-based PowerMESH™ layout. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

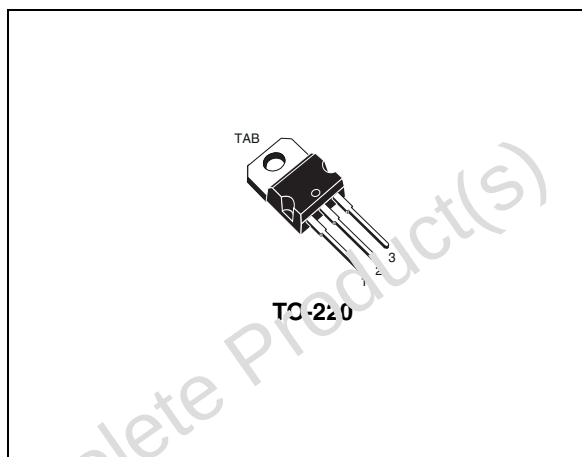


Figure 1. Internal schematic diagram

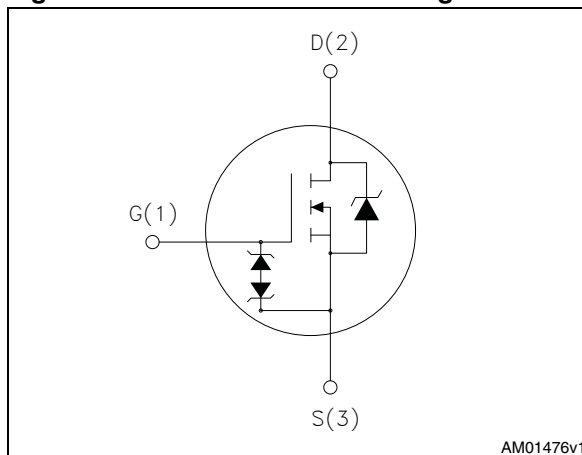


Table 1. Device summary

| Order code | Marking  | Package | Packaging |
|------------|----------|---------|-----------|
| STP10NK50Z | P10NK50Z | TO-220  | Tube      |

## Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

| Symbol             | Parameter                                                         | Value      | Unit                  |
|--------------------|-------------------------------------------------------------------|------------|-----------------------|
| $V_{DSS}$          | Drain-source voltage                                              | 500        | V                     |
| $V_{GS}$           | Gate-source voltage                                               | $\pm 30$   | V                     |
| $I_D$              | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$  | 9          | A                     |
| $I_D$              | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$ | 5.7        | A                     |
| $I_{DM}^{(1)}$     | Drain current (pulsed)                                            | 36         | A                     |
| $P_{TOT}$          | Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$           | 125        | W                     |
|                    | Derating factor                                                   | 1          | W/ $^{\circ}\text{C}$ |
| $V_{esd}(G-S)$     | G-S ESD (HBM $C=100\text{ pF}$ , $R=1.5\text{ k}\Omega$ )         | 4000       | V                     |
| $dv/dt^{(2)}$      | Peak diode recovery voltage slope                                 | 4.5        | V/ns                  |
| $T_J$<br>$T_{stg}$ | Operating junction temperature<br>Storage temperature             | -55 to 150 | $^{\circ}\text{C}$    |

1. Pulse width limited by safe operating area.

2.  $I_{SD} \leq 9\text{ A}$ ,  $di/dt \leq 200\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq T_{Jmax}$

**Table 3. Thermal data**

| Symbol         | Parameter                                      | Value | Unit                        |
|----------------|------------------------------------------------|-------|-----------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max           | 1     | $^{\circ}\text{C}/\text{W}$ |
| $R_{thja}$     | Thermal resistance junction-ambient max        | 62.5  | $^{\circ}\text{C}/\text{W}$ |
| $T_l$          | Maximum lead temperature for soldering purpose | 300   | $^{\circ}\text{C}$          |

**Table 4. Avalanche characteristics**

| Symbol   | Parameter                                                                                                        | Value | Unit |
|----------|------------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AS}$ | Avalanche current, repetitive or not-repetitive (pulse width limited by $T_J$ max)                               | 9     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_J=25\text{ }^{\circ}\text{C}$ , $I_D=I_{AR}$ , $V_{DD}=50\text{ V}$ ) | 230   | mJ   |

## 2 Electrical characteristics

(T<sub>CASE</sub>=25°C unless otherwise specified)

**Table 5. On/off states**

| Symbol               | Parameter                                             | Test conditions                                                             | Min. | Typ. | Max.    | Unit     |
|----------------------|-------------------------------------------------------|-----------------------------------------------------------------------------|------|------|---------|----------|
| V <sub>(BR)DSS</sub> | Drain-source breakdown voltage                        | I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0                                  | 500  |      |         | V        |
| I <sub>DSS</sub>     | Zero gate voltage drain current (V <sub>GS</sub> = 0) | V <sub>DS</sub> = 500 V<br>V <sub>DS</sub> = 500 V, T <sub>C</sub> = 125 °C |      |      | 1<br>50 | μA<br>μA |
| I <sub>GSS</sub>     | Gate body leakage current (V <sub>DS</sub> = 0)       | V <sub>GS</sub> = ±20 V                                                     |      |      | ±10     | μA       |
| V <sub>GS(th)</sub>  | Gate threshold voltage                                | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 100 μA                 | 3    | 3.75 | 4.5     | V        |
| R <sub>DS(on)</sub>  | Static drain-source on resistance                     | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.5 A                              |      | 0.55 | 0.7     | Ω        |

**Table 6. Dynamic**

| Symbol                             | Parameter                     | Test conditions                                        | Min. | Typ. | Max. | Unit |
|------------------------------------|-------------------------------|--------------------------------------------------------|------|------|------|------|
| C <sub>iss</sub>                   | Input capacitance             | V <sub>DS</sub> = 25 V, f = 1 MHz, V <sub>GS</sub> = 0 | -    | 1219 | -    | pF   |
| C <sub>oss</sub>                   | Output capacitance            |                                                        |      | 159  |      | pF   |
| C <sub>rss</sub>                   | Reverse transfer capacitance  |                                                        |      | 40   |      | pF   |
| C <sub>oss eq</sub> <sup>(1)</sup> | Equivalent output capacitance | V <sub>GS</sub> = 0, V <sub>DS</sub> = 0 to 640 V      | -    | 806  | -    | pF   |
| Q <sub>g</sub>                     | Total gate charge             | V <sub>DD</sub> = 400 V, I <sub>D</sub> = 9 A          | -    | 39.2 | -    | nC   |
| Q <sub>gs</sub>                    | Gate-source charge            | V <sub>GS</sub> = 10 V                                 |      | 7.42 |      | nC   |
| Q <sub>gd</sub>                    | Gate-drain charge             | See <a href="#">Figure 15</a>                          |      | 20.7 |      | nC   |

1. C<sub>oss eq</sub> is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>

**Table 7. Switching times**

| Symbol       | Parameter           | Test conditions                                                                                                         | Min. | Typ. | Max. | Unit |
|--------------|---------------------|-------------------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD}=250\text{ V}$ , $I_D=4.5\text{ A}$ ,<br>$R_G=4.7\Omega$ , $V_{GS}=10\text{ V}$<br>See <a href="#">Figure 16</a> | -    | 19   | -    | ns   |
| $t_r$        | Rise time           |                                                                                                                         |      | 17   |      | ns   |
| $t_{d(off)}$ | Turn-off delay Time |                                                                                                                         | -    | 43   | -    | ns   |
| $t_f$        | Fall time           |                                                                                                                         |      | 15   |      | ns   |

**Table 8. Source drain diode**

| Symbol          | Parameter                     | Test conditions                                                                                                         | Min | Typ.  | Max. | Unit          |
|-----------------|-------------------------------|-------------------------------------------------------------------------------------------------------------------------|-----|-------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                         | -   |       | 9    | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                         | -   |       | 36   | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD}=9\text{ A}$ , $V_{GS}=0$                                                                                        | -   |       | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD}=9\text{ A}$ ,<br>$di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD}=35\text{ V}$                                   | -   | 268   |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                         |     | 1.83  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                         |     | 13.7  |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD}=9\text{ A}$ ,<br>$di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD}=35\text{ V}$ , $T_j=150\text{ }^\circ\text{C}$ | -   | 343   |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                         |     | 2.6   |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                         |     | 15.15 |      | A             |

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration= 300 $\mu\text{s}$ , duty cycle 1.5%

**Table 9. Gate-source zener diode**

| Symbol           | Parameter                     | Test conditions                       | Min. | Typ. | Max. | Unit |
|------------------|-------------------------------|---------------------------------------|------|------|------|------|
| $BV_{GSO}^{(1)}$ | Gate-source breakdown voltage | $I_{GS}=\pm 1\text{ mA}$ (open drain) | 30   | -    |      | V    |

1. The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

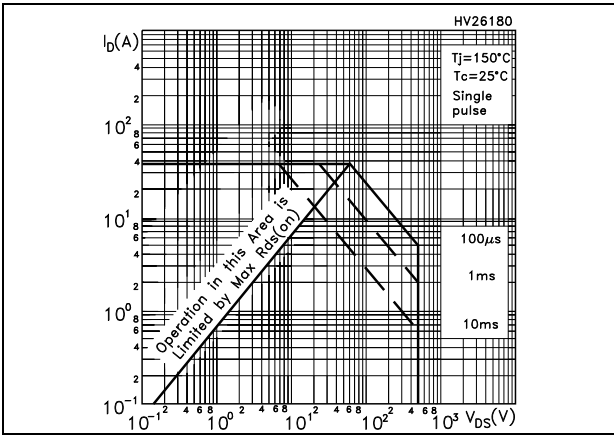


Figure 3. Thermal impedance

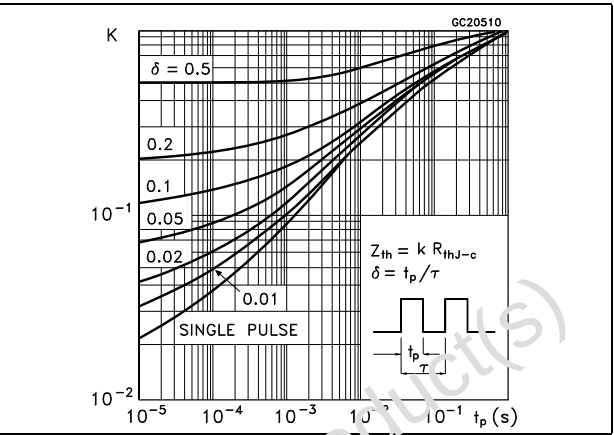


Figure 4. Output characteristics

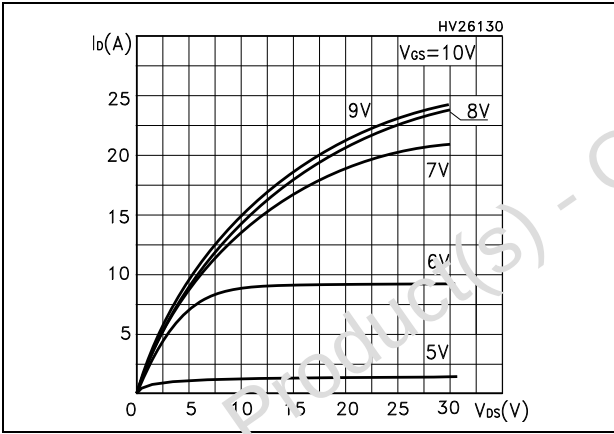


Figure 5. Transfer characteristics

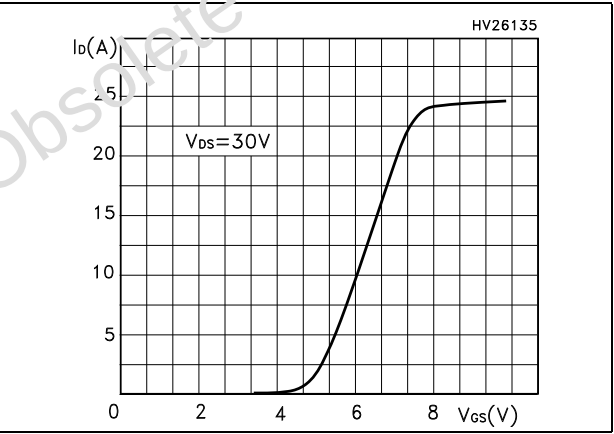


Figure 6. Normalized BV\_DS vs temperature

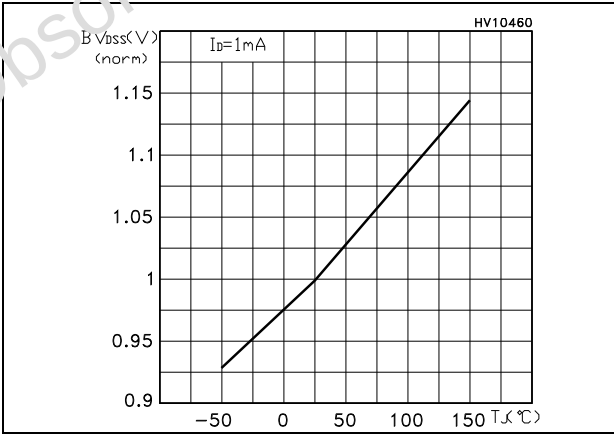


Figure 7. Static drain-source on resistance

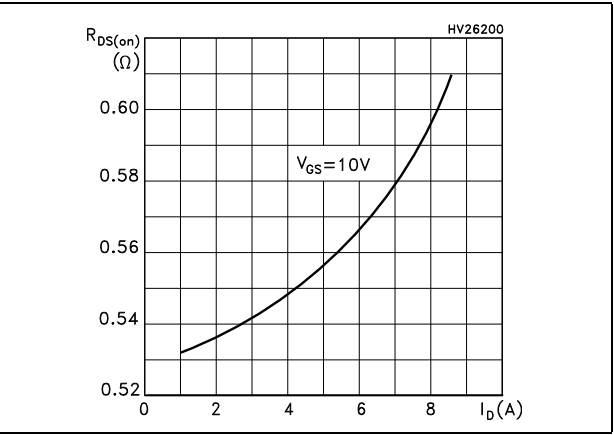


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

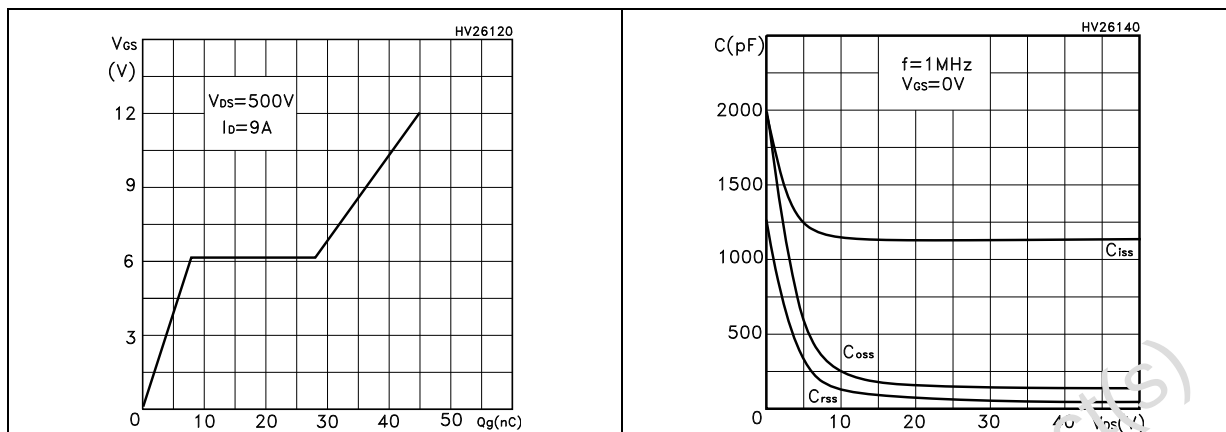


Figure 10. Normalized gate threshold voltage vs temperature Figure 11. Normalized on resistance vs temperature

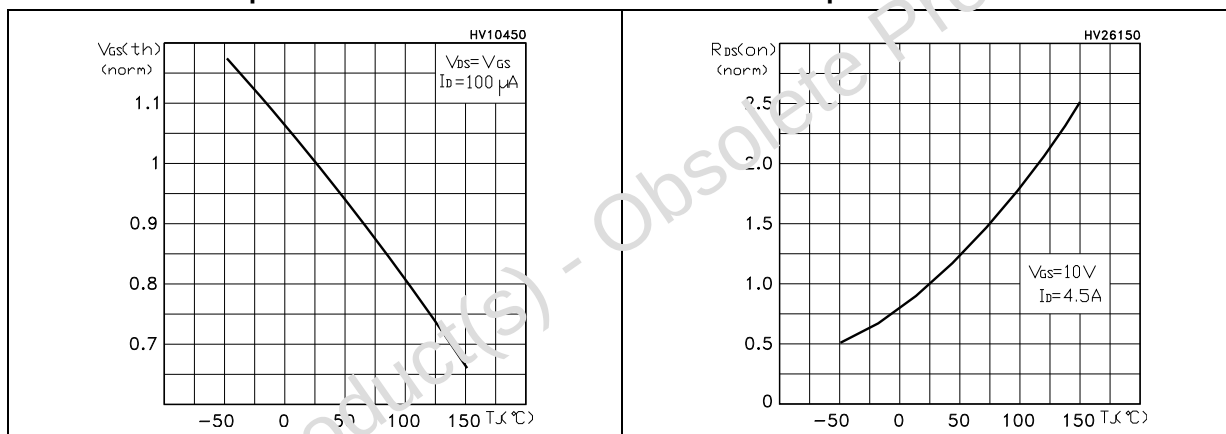
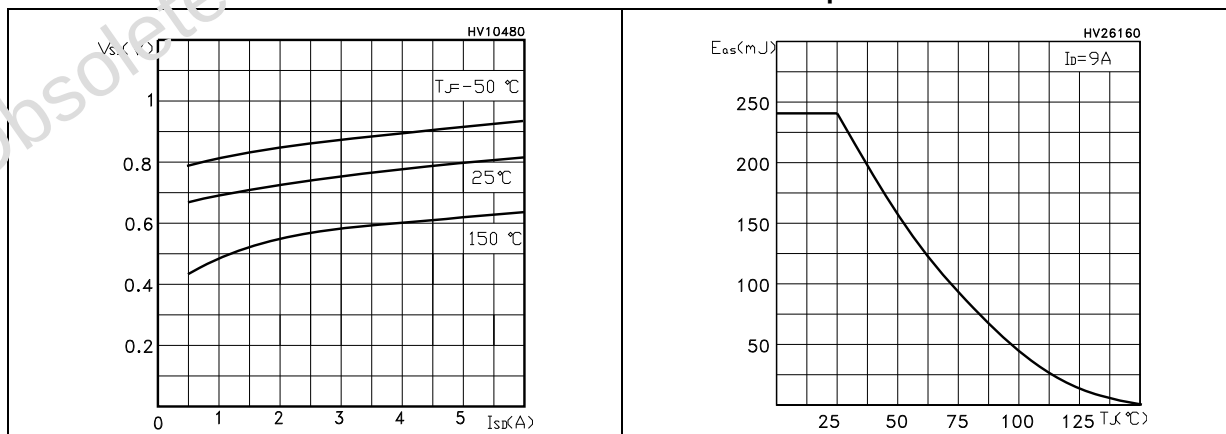
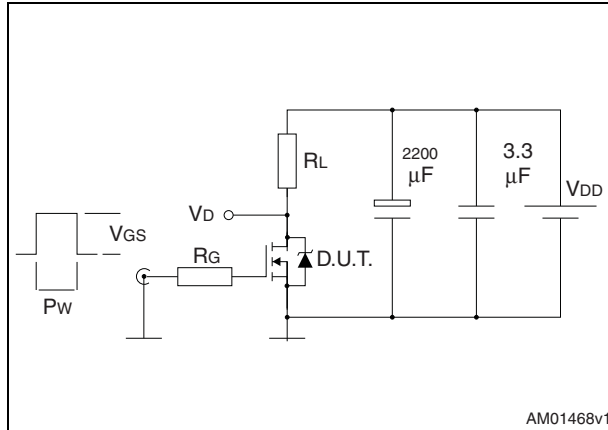


Figure 12. Source-drain diode forward characteristics Figure 13. Maximum avalanche energy vs temperature

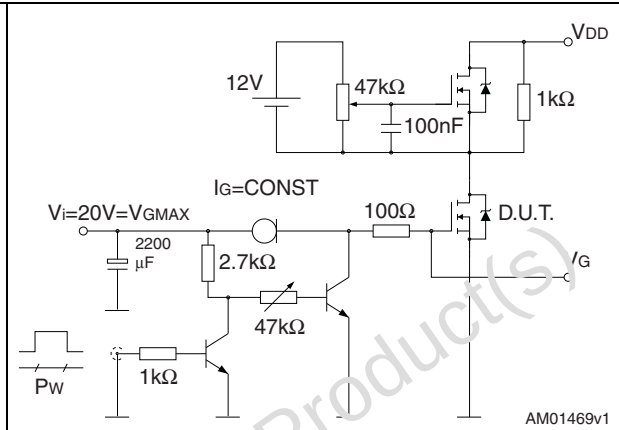


### 3 Test circuit

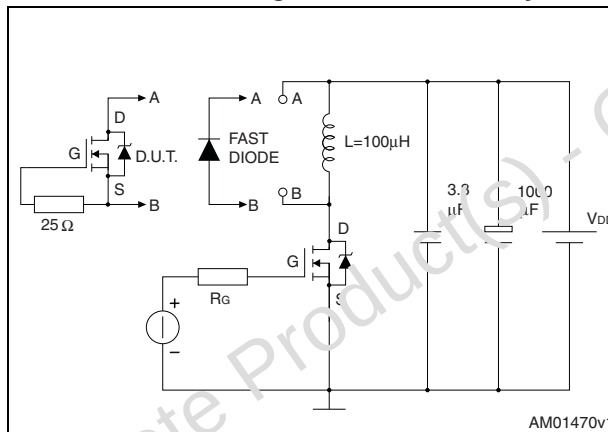
**Figure 14. Switching times test circuit for resistive load**



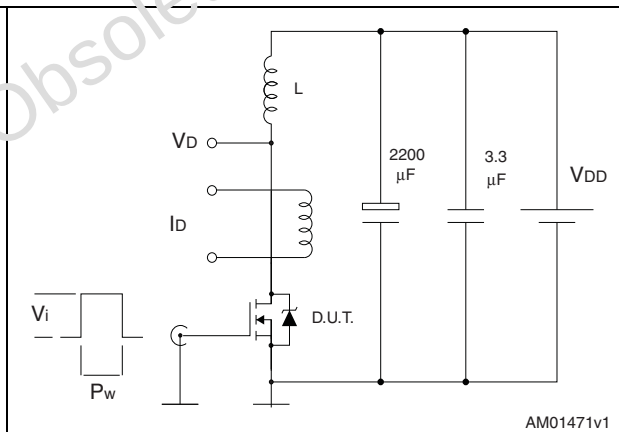
**Figure 15. Gate charge test circuit**



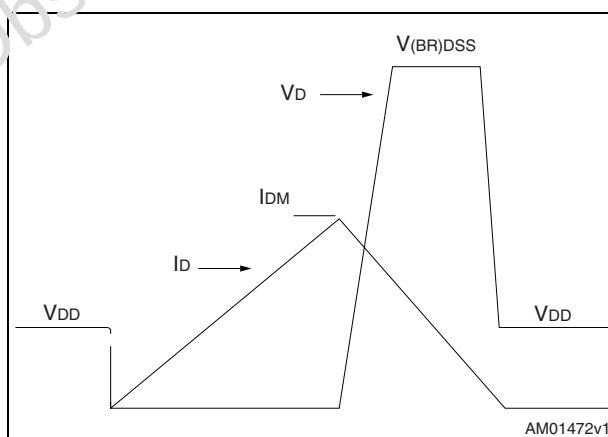
**Figure 16. Test circuit for inductive load switching and diode recovery times**



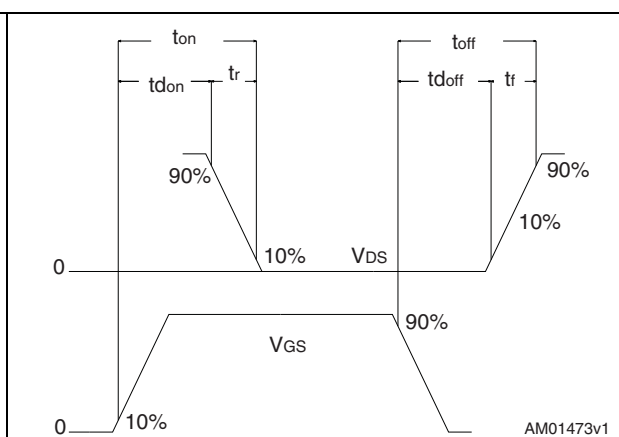
**Figure 17. Uncamped inductive load test circuit**



**Figure 18. Unclamped inductive waveform**



**Figure 19. Switching time waveform**



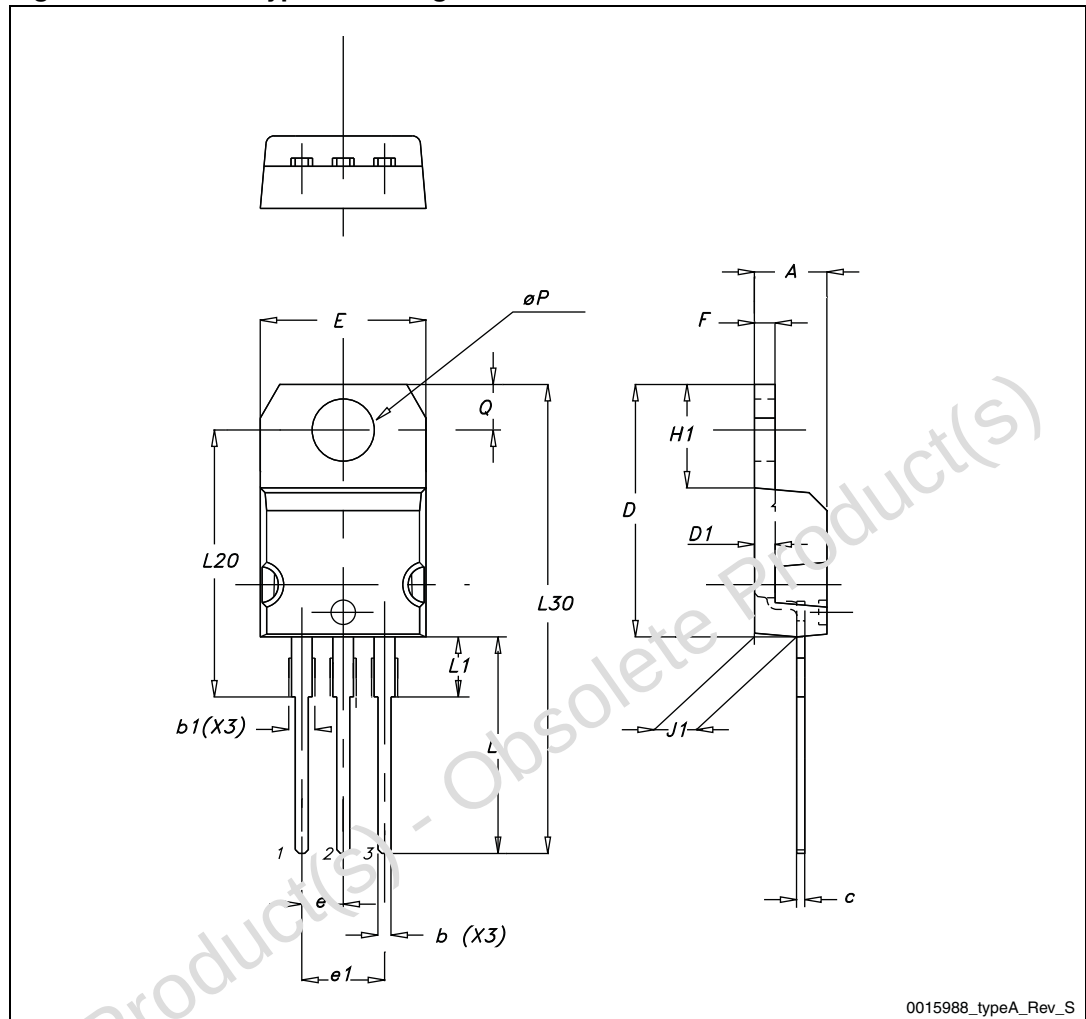
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

**Table 10. TO-220 type A mechanical data**

| Dim. | mm    |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.40  |       | 4.60  |
| b    | 0.61  |       | 0.80  |
| b1   | 1.14  |       | 1.70  |
| c    | 0.48  |       | 0.70  |
| D    | 15.25 |       | 15.75 |
| D1   |       | 1.27  |       |
| E    | 10    |       | 10.40 |
| e    | 2.40  |       | 2.70  |
| e1   | 4.95  |       | 5.15  |
| F    | 1.23  |       | 1.32  |
| H1   | 6.20  |       | 6.60  |
| J1   | 2.40  |       | 2.72  |
| L    | 13    |       | 14    |
| L1   | 3.50  |       | 3.93  |
| L20  |       | 16.40 |       |
| L30  |       | 28.90 |       |
| ØP   | 3.75  |       | 3.85  |
| Q    | 2.65  |       | 2.95  |

Figure 20. TO-220 type A drawing



## 5 Revision history

**Table 11. Document revision history**

| Date        | Revision | Changes                                                            |
|-------------|----------|--------------------------------------------------------------------|
| 01-Jul-2005 | 1        | First release.                                                     |
| 08-Sep-2005 | 2        | Inserted ecopack indication                                        |
| 15-Mar-2012 | 3        | The part number STF10NK50Z has been moved to a separate datasheet. |

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